

11-6-2012

# Semiconductor integrated circuit chip, multilayer chip capacitor and semiconductor integrated circuit chip package

Byoung Hwa Lee

Min Cheol Park

Ho Cheol Kwak

Haixin Ke

Todd Harvey Hubing

Follow this and additional works at: [https://tigerprints.clemson.edu/clemson\\_patents](https://tigerprints.clemson.edu/clemson_patents)

---

## Recommended Citation

Lee, Byoung Hwa; Park, Min Cheol; Kwak, Ho Cheol; Ke, Haixin; and Hubing, Todd Harvey, "Semiconductor integrated circuit chip, multilayer chip capacitor and semiconductor integrated circuit chip package" (2012). *Clemson Patents*. 307.  
[https://tigerprints.clemson.edu/clemson\\_patents/307](https://tigerprints.clemson.edu/clemson_patents/307)

This Patent is brought to you for free and open access by TigerPrints. It has been accepted for inclusion in Clemson Patents by an authorized administrator of TigerPrints. For more information, please contact [kokeefe@clemson.edu](mailto:kokeefe@clemson.edu).



(12) **United States Patent**  
**Lee et al.**

(10) **Patent No.:** **US 8,304,854 B2**  
(45) **Date of Patent:** **Nov. 6, 2012**

(54) **SEMICONDUCTOR INTEGRATED CIRCUIT CHIP, MULTILAYER CHIP CAPACITOR AND SEMICONDUCTOR INTEGRATED CIRCUIT CHIP PACKAGE**

7,319,268	B2 *	1/2008	Watanabe et al. ....	257/686
2002/0074643	A1 *	6/2002	Yamazaki et al. ....	257/692
2003/0234434	A1	12/2003	Matsushima	
2006/0097365	A1 *	5/2006	Song et al. ....	257/666
2008/0258259	A1	10/2008	Osaka et al.	
2008/0266031	A1	10/2008	Uematsu et al.	

(75) Inventors: **Byoung Hwa Lee**, Gyunggi-do (KR); **Min Cheol Park**, Gyunggi-do (KR); **Ho Cheol Kwak**, Clemson, SC (US); **Haixin Ke**, Clemson, SC (US); **Todd Harvey Hubing**, Clemson, SC (US)

**FOREIGN PATENT DOCUMENTS**

JP	59-124744	A	7/1984
JP	59-185821	U	12/1984
JP	63-158828	A	7/1988
JP	06-283384	A	10/1994

(Continued)

(73) Assignees: **Samsung Electro-Mechanics Co., Ltd.**, Gyunggi-Do (KR); **Clemson University**, Clemson, SC (US)

**OTHER PUBLICATIONS**

(\* ) Notice: Subject to any disclaimer, the term of this patent is extended or adjusted under 35 U.S.C. 154(b) by 327 days.

IBM Technical Description Bulletin, DOc. ID : NN80044919, "Decoupling Capacitor Implementation Scheme", Apr. 1980.\*

(Continued)

(21) Appl. No.: **12/270,457**

*Primary Examiner* — Matthew Reames

(22) Filed: **Nov. 13, 2008**

*Assistant Examiner* — Ermias Woldegeorgis

(65) **Prior Publication Data**

US 2010/0117192 A1 May 13, 2010

(74) *Attorney, Agent, or Firm* — McDermott Will & Emery LLP

(51) **Int. Cl.**

**H01L 29/92** (2006.01)

(57) **ABSTRACT**

(52) **U.S. Cl.** ..... **257/532**; 361/301.1; 361/306.1; 361/306.2; 361/306.3; 361/307; 361/308.1; 361/310; 361/734; 361/738; 257/535; 257/E23.057; 257/E29.343

Disclosed are a semiconductor integrated circuit chip, a multilayer chip capacitor, and a semiconductor integrated circuit chip package. The semiconductor integrated circuit chip includes a semiconductor integrated circuit chip body, an input/output terminal disposed on the outside of the semiconductor integrated circuit chip body, and a decoupling capacitor disposed at a side face of the semiconductor integrated circuit chip body and electrically connected to the input/output terminal. The semiconductor integrated circuit chip can be obtained, which can maintain an impedance of a power distribution network below a target impedance in a wide frequency range, particularly at a high frequency, by minimizing an inductance between a decoupling capacitor and a semiconductor integrated circuit chip.

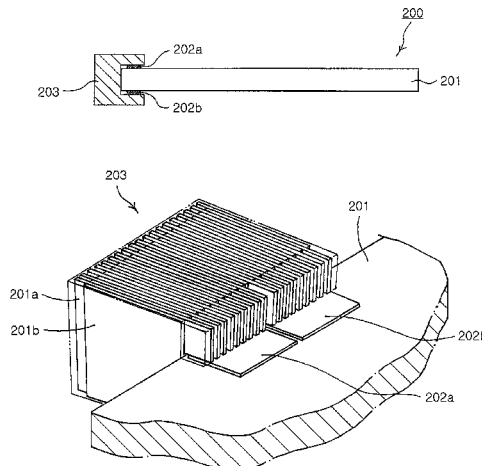
(58) **Field of Classification Search** ..... 257/532, 257/535, E23.057, E29.343, 301.1, 306.1, 257/306.2, 306.3, 307, 308, 310, 734, 738  
See application file for complete search history.

(56) **References Cited**

**U.S. PATENT DOCUMENTS**

5,387,814	A *	2/1995	Baudouin et al. ....	257/690
6,222,246	B1 *	4/2001	Mak et al. ....	257/532
6,964,584	B2 *	11/2005	Zhong et al. ....	439/620.21

**27 Claims, 7 Drawing Sheets**



# US 8,304,854 B2

Page 2

---

## FOREIGN PATENT DOCUMENTS

JP	11-176694 A	7/1999
JP	2000306764 A *	11/2000
JP	2002164462 A	6/2002
JP	2004-031432 A	1/2004
JP	2006-086359 A	3/2006
JP	2006-278355 A	12/2006
JP	2007-173669	7/2007
JP	2007-243229	9/2007
JP	2008-004853	1/2008
JP	2008-258312 A	10/2008

JP 2008-270581 A 11/2008

## OTHER PUBLICATIONS

Japanese Office Action, with English translation, issued in Japanese Patent Application No. 2009-149505, dated Jun. 27, 2011.

Japanese Office Action, w/ English translation thereof, issued in Japanese Patent Application No. 2009-149505, dated Dec. 6, 2011.

Japanese Office Action, and English translation thereof, issued in Japanese Patent Application No. 2009-149505 dated Jul. 10, 2012.

\* cited by examiner

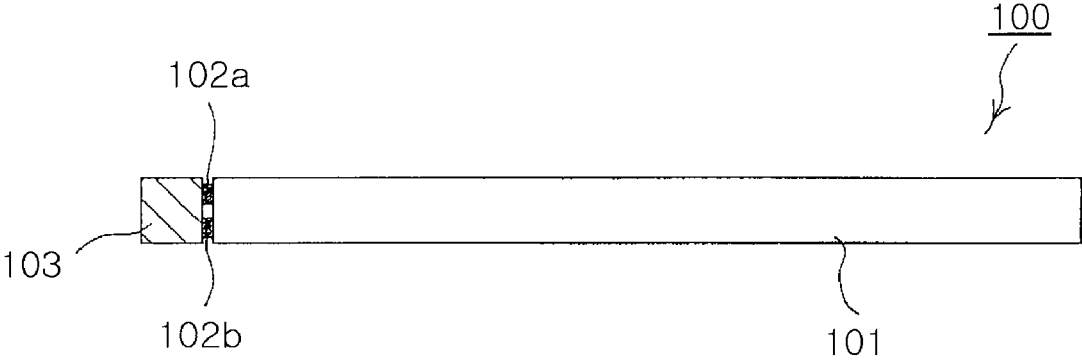


FIG. 1A

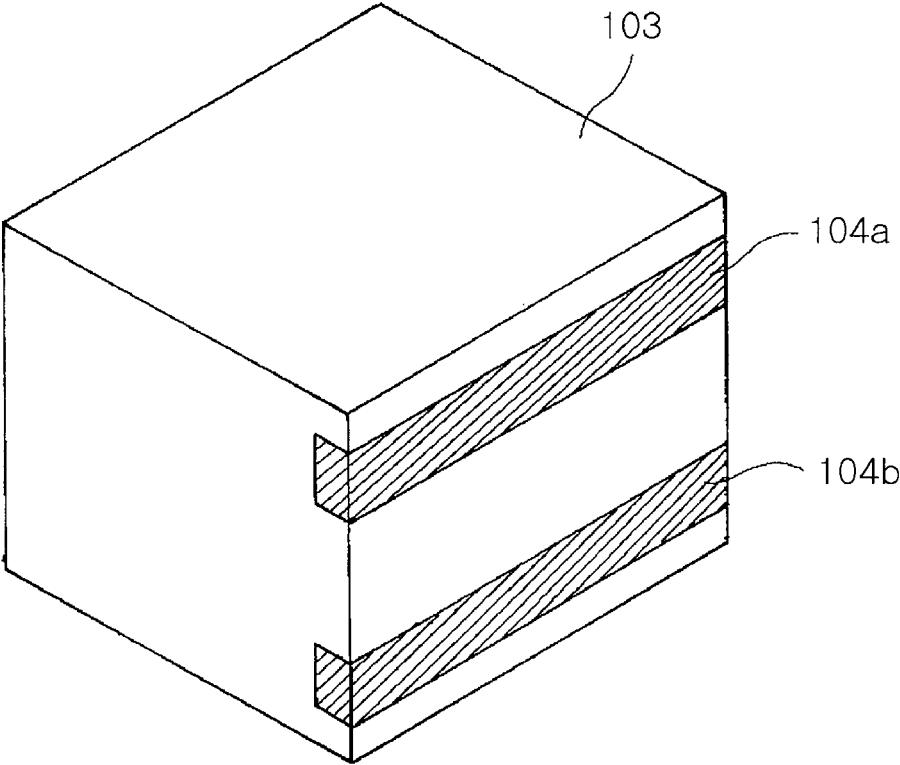


FIG. 1B

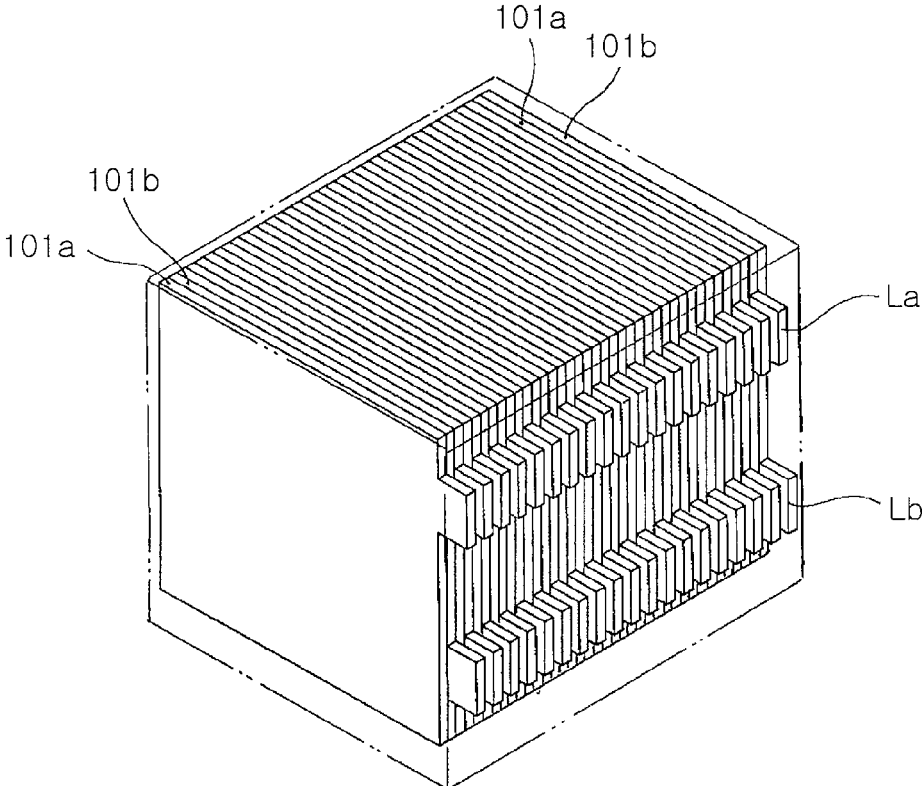


FIG. 1C

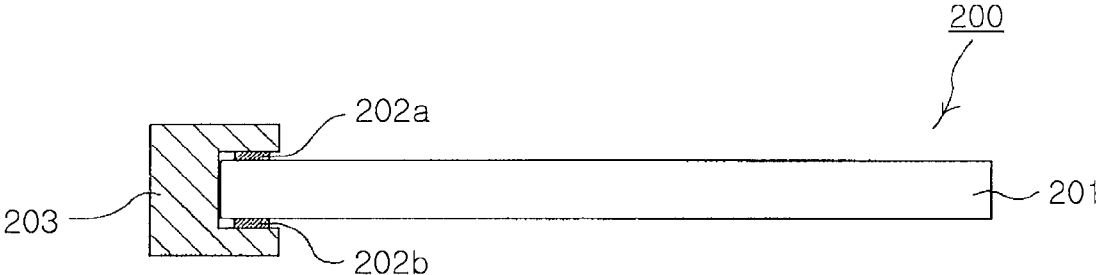


FIG. 2A

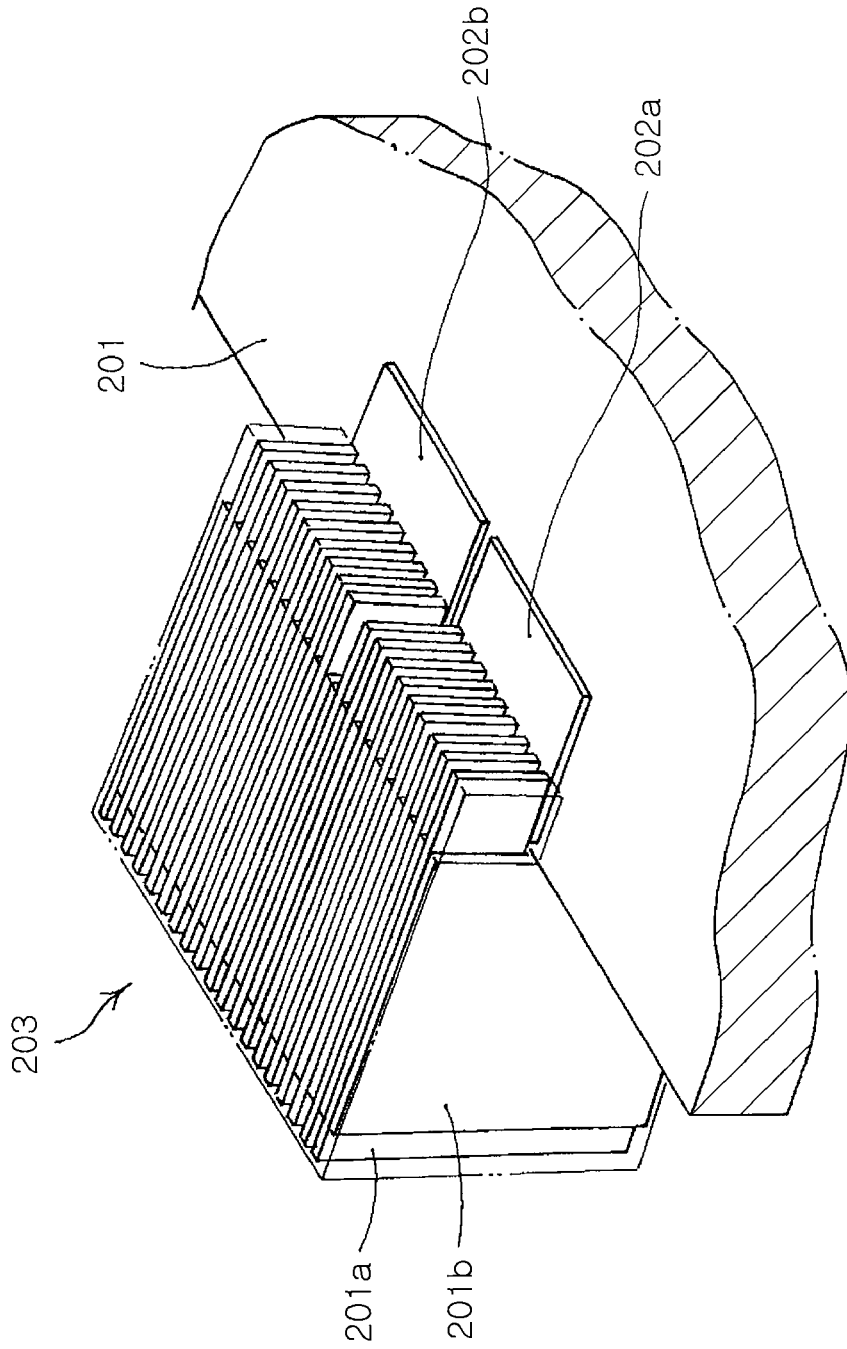


FIG. 2B

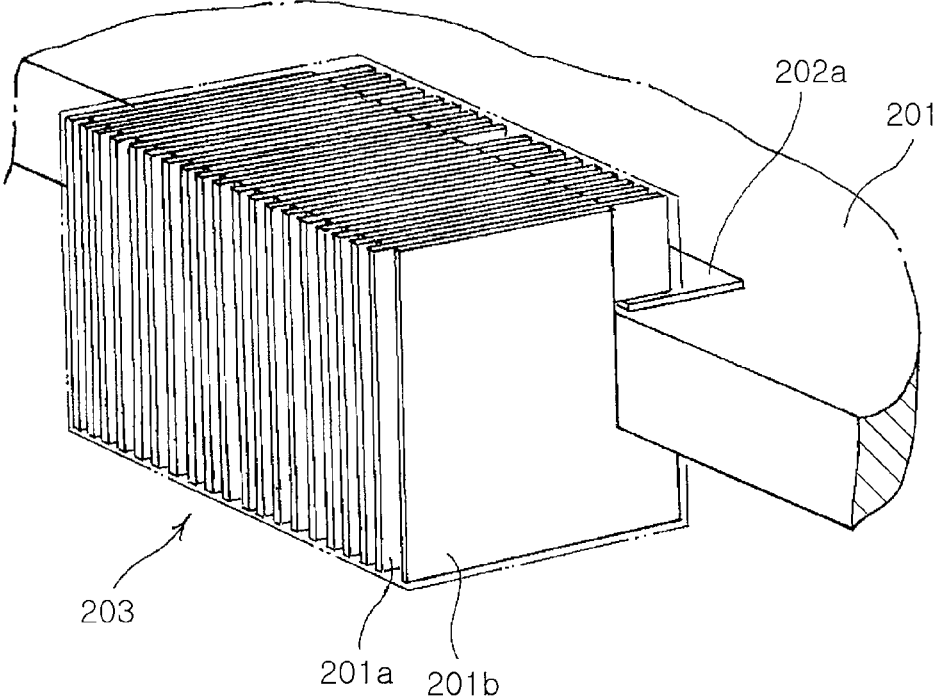


FIG. 2C

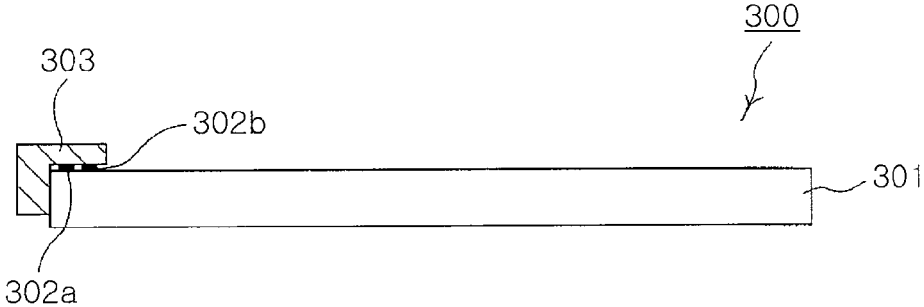


FIG. 3A

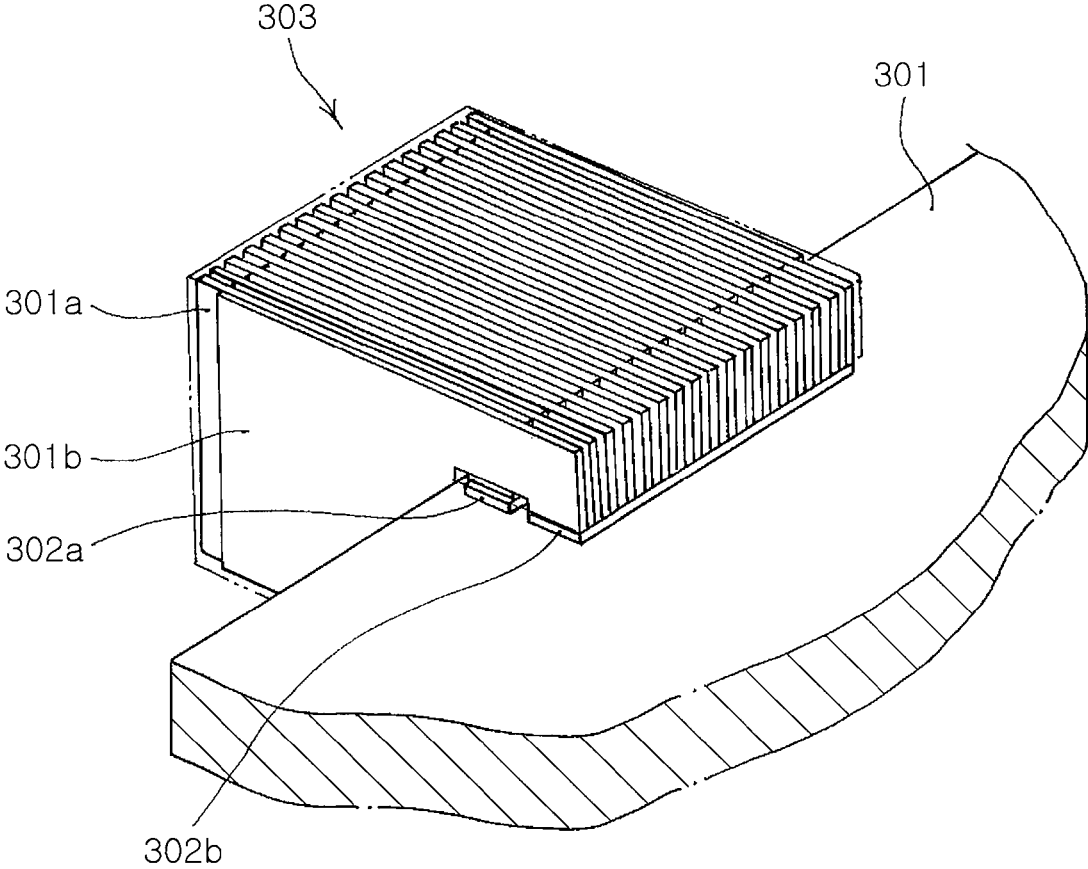


FIG. 3B



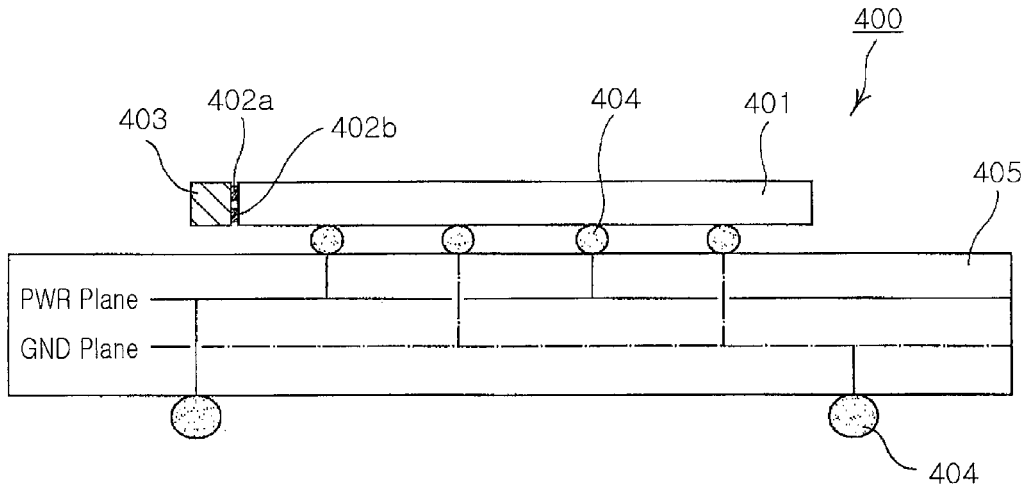


FIG. 4

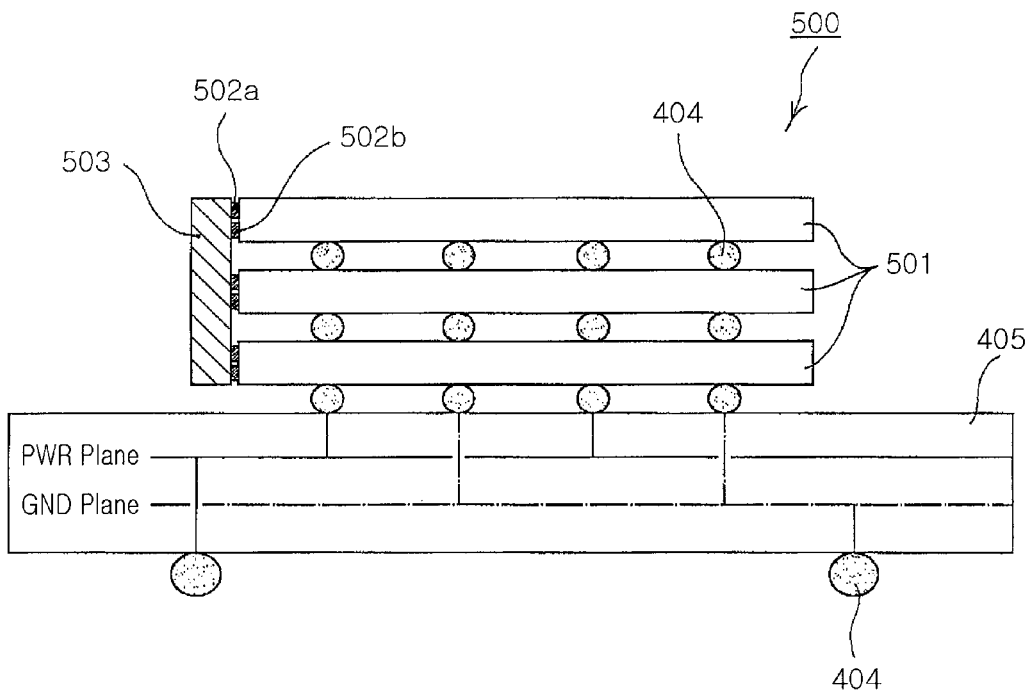
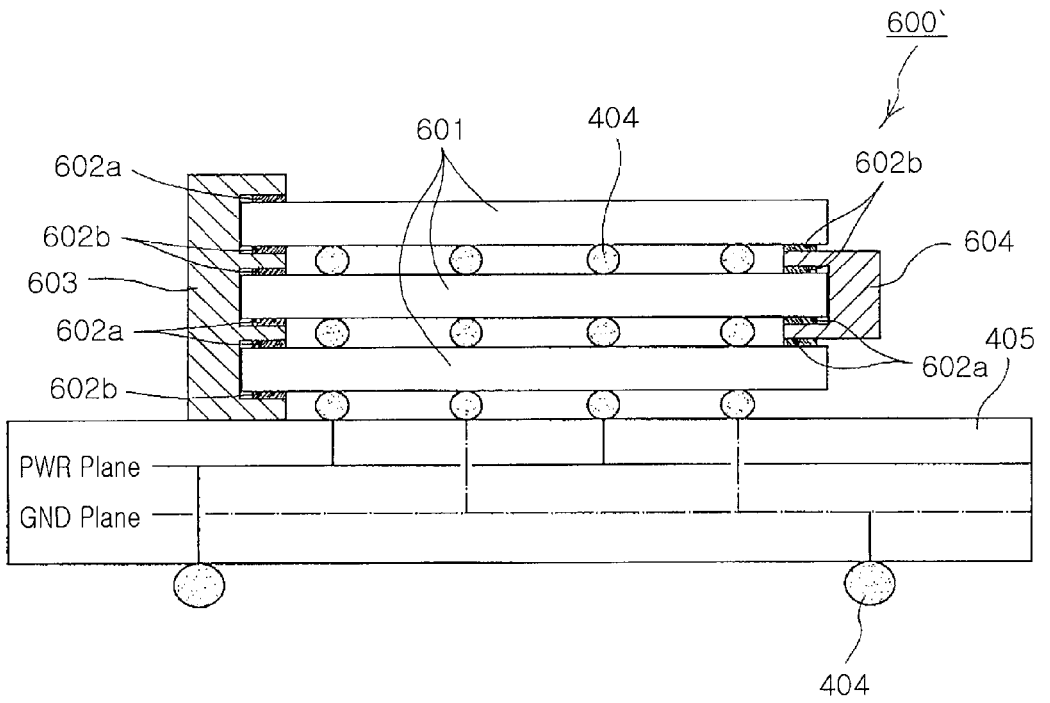
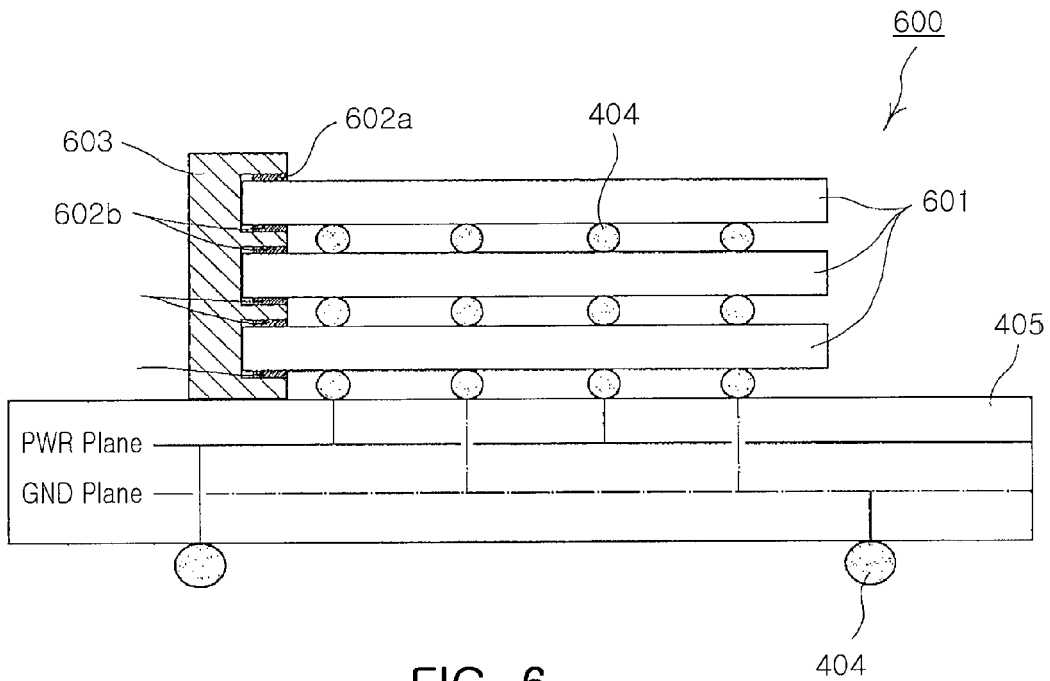


FIG. 5



**SEMICONDUCTOR INTEGRATED CIRCUIT  
CHIP, MULTILAYER CHIP CAPACITOR AND  
SEMICONDUCTOR INTEGRATED CIRCUIT  
CHIP PACKAGE**

BACKGROUND OF THE INVENTION

1. Field of the Invention

The present invention relates to a semiconductor integrated circuit chip, a multilayer chip capacitor and a semiconductor integrated circuit chip package.

2. Description of the Related Art

A semiconductor integrated circuit chip such as a micro processor unit (MPU) chip is continuously increasing in operating frequency, and the integration density thereof is also increasing. For this reason, current consumption of the semiconductor integrated circuit chip is continuously increased, and its operation voltage is lowered. Thus, it becomes more difficult to suppress noise of a DC supply voltage, which occurs due to a sudden fluctuation of a load current of the semiconductor integrated circuit chip.

That is, as can be seen from the following equation, the target impedance ( $Z_{target}$ ) is being gradually lowered.

$$Z_{target} = V_p \times AR / I = Vr / I$$

where  $V_p$  represents a power voltage,  $AR$  represents an allowed ripple,  $I$  represents a current consumed by an MPU, and  $Vr$  represents an allowed ripple voltage.

In general, the allowed ripple voltage ( $Vr$ ) ranges from about 5% to about 10% of a power voltage. The target impedance ( $Z_{target}$ ) must be met not just at a DC current (DC) but also at every frequency at which a transient current exists. In the case of a personal computer (PC) or a notebook computer, a transient current exists even in the very high frequency range because of the use of high-speed semiconductor integrated circuits, i.e., high-speed central processing units (CPUs). Thus, the target impedance must be satisfied even in a wide frequency range.

A decoupling capacitor can remove the voltage noise by supplying a current to the semiconductor integrated circuit chip at the time of the sudden fluctuation of the load current. However, even with the decoupling capacitor, it is not easy to meet the target impedance even at a high frequency. Therefore, there is a need for a method for maintaining an impedance of a power distribution network below the target impedance in a wide frequency range, particularly at the high frequency.

SUMMARY OF THE INVENTION

An aspect of the present invention provides a semiconductor integrated circuit chip capable of maintaining an impedance of a power distribution network below a target impedance in a wide frequency range, particularly at a high frequency, by minimizing an inductance between a decoupling capacitor and a semiconductor integrated circuit chip.

An aspect of the present invention also provides a multilayer chip capacitor that can be used for the semiconductor integrated circuit chip, and a package including the semiconductor integrated circuit chip.

According to an aspect of the present invention, there is provided a semiconductor integrated circuit chip including: a semiconductor integrated circuit chip body; an input/output terminal disposed on the outside of the semiconductor integrated circuit chip body; and a decoupling capacitor disposed at a side face of the semiconductor integrated circuit chip body and electrically connected to the input/output terminal.

The input/output terminal may be placed at the side face of the semiconductor integrated circuit chip body at which the decoupling capacitor is disposed. The input/output terminal may be disposed on at least one of top and bottom faces of the semiconductor integrated circuit chip body.

The decoupling capacitor may be a multilayer chip capacitor, which includes a capacitor body including therein a stack of a plurality of dielectric layers; first and second internal electrodes having opposite polarity and alternated with each other, with the dielectric layer between each alternate set of the first and second internal electrodes; and first and second external electrodes disposed on the outside of the capacitor body and respectively connected to the first and second internal electrodes.

The first and second external electrodes may be disposed in one direction on a side face of the capacitor body facing the semiconductor integrated circuit chip body, and are spaced apart from each other.

The input/output terminal may include first and second electrode pads for electrical connection with the first and second external electrodes, respectively.

The first and second electrode pads may be disposed on both top and bottom faces of the semiconductor integrated circuit chip body.

The first and second electrode pads on the same face may be spaced apart from each other in a direction perpendicular to a direction from the semiconductor integrated circuit chip body toward the decoupling capacitor.

The second electrode pad on the bottom face of the semiconductor integrated circuit chip body may face the first electrode pad on the top face of the semiconductor integrated circuit chip body. The plurality of dielectric layers may be stacked in the same direction as a direction in which the first and second electrode pads are disposed.

The first and second electrode pads may be disposed on a top or bottom face of the semiconductor integrated circuit chip body. The first and second electrode pads may be spaced apart from each other in a direction from the semiconductor integrated circuit chip body toward the decoupling capacitor.

According to another aspect of the present invention, there is provided a multilayer chip capacitor including: a capacitor body having a shape defined by top and bottom faces facing each other and a side face therebetween, and having therein a stack of a plurality of dielectric layers; first and second internal electrodes having opposite polarity and alternated with each other, with the dielectric layer between each alternate set of the first and second internal electrodes; and first and second external electrodes disposed on the outside of the capacitor body and electrically connected to the first and second internal electrodes, respectively. The capacitor body includes at least one protrusion extending from one side face of the capacitor body, and the first and second external electrodes are disposed on at least one of faces forming the protrusion.

The capacitor body may include one protrusion extending from the top face and the side face of the capacitor body. The first and second external electrodes may be disposed on a face facing a lower portion of the capacitor body among faces forming the protrusion. The first and second external electrodes may be spaced apart from each other in a direction from the protrusion toward the capacitor body. The plurality of dielectric layers may be stacked in a direction perpendicular to a direction in which the first and second external electrodes are disposed.

The capacitor body may include a first protrusion extending from the top face and the side face of the capacitor body, and a second protrusion extending from the bottom face and the side face of the capacitor body. The first and second

3

external electrodes may be disposed on a face facing a lower portion of the capacitor body among faces forming the first protrusion and on a face facing an upper portion of the capacitor body among faces forming the second protrusion.

The first and second external electrodes at the first protrusion may be spaced from each other in a direction perpendicular to a direction from the first protrusion toward the capacitor body. The first and second external electrodes at the second protrusion may be spaced apart from each other in a direction perpendicular to a direction from the second protrusion toward the capacitor body. The second external electrode at the second protrusion may face the first external electrode at the first protrusion. The plurality of dielectric layers may be stacked in a direction in which the first and second external electrodes are disposed.

The capacitor body may include a plurality of protrusions disposed in one direction and spaced apart from each other.

According to another aspect of the present invention, there is provided a semiconductor integrated circuit chip package including: a package substrate; and a semiconductor integrated circuit chip mounted on the package substrate and including a semiconductor integrated circuit chip body, an input/output terminal disposed on the outside of the semiconductor integrated circuit chip body, and a decoupling capacitor disposed at a side face of the semiconductor integrated circuit chip body and electrically connected to the input/output terminal.

The semiconductor integrated circuit chip may include a plurality of semiconductor integrated circuit chips stacked on top of each other on the package substrate.

The decoupling capacitor may be a common decoupling capacitor electrically connected to at least two semiconductor integrated circuit chips of the plurality of semiconductor integrated circuit chips.

The decoupling capacitor may include: at least one protrusion extending from a side face of the decoupling capacitor facing the semiconductor integrated circuit chip body; and first and second external electrodes disposed at a face forming the protrusion and electrically connected to the input/output terminal.

The protrusion may be placed in a space between an adjacent set of the semiconductor integrated circuit chips.

The semiconductor integrated circuit chip package may further include an external electrode provided on one side of the decoupling capacitor and contacting a top face of the package substrate to be electrically connected with the package substrate. The semiconductor integrated circuit chip body may be electrically connected with the package substrate through the decoupling capacitor.

#### BRIEF DESCRIPTION OF THE DRAWINGS

The above and other aspects, features and other advantages of the present invention will be more clearly understood from the following detailed description taken in conjunction with the accompanying drawings, in which:

FIG. 1A is a cross-sectional view of a semiconductor integrated circuit chip according to an exemplary embodiment of the present invention;

FIG. 1B is a perspective view of a decoupling capacitor disposed at a side face of the semiconductor integrated circuit chip of FIG. 1A;

FIG. 1C is a view of the interior of a capacitor body of the decoupling capacitor of FIG. 1B;

FIG. 2A is a cross-sectional view of a semiconductor integrated circuit chip according to another exemplary embodiment of the present invention;

4

FIGS. 2B and 2C are perspective views illustrating the disposition of a decoupling capacitor at a semiconductor integrated circuit chip body of FIG. 2A;

FIG. 3A is a cross-sectional view of a semiconductor integrated circuit chip according to still another exemplary embodiment of the present invention;

FIG. 3B is a perspective view illustrating the disposition of a decoupling capacitor at a semiconductor integrated circuit chip body of FIG. 3A;

FIG. 4 is a cross-sectional view of a semiconductor integrated circuit chip package according to an exemplary embodiment of the present invention;

FIG. 5 is a cross-sectional view of an alternative version of the semiconductor integrated circuit chip package of FIG. 4;

FIG. 6 is a cross-sectional view of a semiconductor integrated circuit chip package according to another exemplary embodiment of the present invention; and

FIG. 7 is a cross-sectional view of an alternative version of the semiconductor integrated circuit chip package of FIG. 6.

#### DETAILED DESCRIPTION OF THE PREFERRED EMBODIMENT

Exemplary embodiments of the present invention will now be described in detail with reference to the accompanying drawings.

The present invention may, however, be embodied in different forms and should not be constructed as limited to the embodiments set forth herein. Rather, these embodiments are provided so that this disclosure will be thorough and complete, and will fully convey the scope of the present invention to those skilled in the art. In the figures, the dimensions and shapes of elements are exaggerated for clarity of illustration. Like reference numerals refer to like elements throughout.

FIGS. 1A through 1C are views for explaining a semiconductor integrated circuit chip according to an exemplary embodiment of the present invention. FIG. 1A is a cross-sectional view, and FIG. 1B is a perspective view of a decoupling capacitor disposed at a side face of the semiconductor integrated circuit. FIG. 1C illustrates the interior of a capacitor body of the decoupling capacitor of FIG. 1B.

Referring to FIG. 1A, a semiconductor integrated circuit chip 100 according to the current embodiment of the present invention includes a semiconductor integrated circuit chip body 101, input/output terminals 102a and 102b serving as first and second electrode pads, and a decoupling capacitor 103 disposed at a side face of the semiconductor integrated circuit chip body 101. The semiconductor integrated circuit chip body 101 can be used as a central processing unit (CPU) of e.g., a computer and a portable terminal by including therein a logic circuit that can process predetermined information. For example, the semiconductor integrated circuit chip body 101 corresponds to a micro processing unit (MPU) chip. In this case, the semiconductor integrated circuit chip body 101 may be electrically connected to the decoupling capacitor 103 by the input/output terminals 102a and 102b disposed at its side face, i.e., the first and second electrode pads 102a 102b of opposite polarity.

The decoupling capacitor 103 applies a current to the semiconductor integrated circuit chip body 101 at the time of a sudden fluctuation of a load current. Thus, the decoupling capacitor 103 can serve to prevent a defective operation of the semiconductor integrated circuit chip body 101, which is caused by the fluctuation of a power voltage or high-frequency noise. As will be described later, the decoupling capacitor 103 disposed directly at the side face of the semiconductor integrated circuit chip body 101 contributes to

lowering an inductance at a current path with the semiconductor integrated circuit chip body **101**.

Referring to FIGS. **1B** and **1C**, the decoupling capacitor **103** includes a capacitor body having a hexahedron shape, and first and second external electrodes **104a** and **104b** disposed on the outside of the capacitor body. The first and second external electrodes **104a** and **104b** are electrically connected to the first and second electrode pads **102a** and **102b** of FIG. **1A**, respectively. For this electrical connection, as shown in FIG. **1B**, the first and second external electrodes **104a** and **104b** are formed on one side face facing the semiconductor integrated circuit chip body **101** among side faces of the capacitor body. This structure facilitates disposition of the decoupling capacitor **103** at the side face of the semiconductor integrated circuit chip body **101**.

According to the current embodiment, the capacitor body includes a stack of a plurality of dielectric layers. That is, the decoupling capacitor **103** may be a multilayer chip capacitor (MLCC). In the decoupling capacitor **103**, first and second internal electrodes **101a** and **101b** are alternated with each other, with the dielectric layer located between each alternate set of the first and second internal electrodes **101a** and **101b**. In FIG. **1C**, just the first and second internal electrodes **101a** and **101b** are illustrated for the convenience of illustration, but the dielectric layer may be considered to be placed between each alternate set of the first and second internal electrodes **101a** and **101b**. The first internal electrode **101a** includes a lead structure La for connection with the first external electrode **104a**. The second internal electrode **101b** also includes a lead structure Lb for connection with the second external electrode **104a**. Particularly, as shown in FIG. **1C**, the first and second internal electrodes **101a** and **101b** respectively include the lead structures La and Lb extending in the same direction.

The decoupling capacitor **103** is connected directly to the semiconductor integrated circuit chip body **101** to form one structure. In this application, such a structure is referred to as the semiconductor integrated circuit chip **100**. Thus, a current path between the decoupling capacitor **103** and the semiconductor integrated circuit chip body **101** can be very short. If a decoupling capacitor is disposed at a package substrate where a semiconductor integrated circuit chip is mounted, or a mother board for power supply, a current path is relatively elongated between the decoupling capacitor and the semiconductor integrated circuit chip (or a semiconductor integrated circuit chip body). This makes it difficult to make an inductance between the decoupling capacitor and the semiconductor integrated circuit chip below a target value. Difficulties associated with the inductance may become worse at a high frequency of hundreds of MHz or higher. As a result, it may become difficult to meet the target impedance condition.

According to the current embodiment, the decoupling capacitor **103** is disposed directly at the side face of the semiconductor integrated circuit chip body **101**, so that the current path between the two can be minimized. Accordingly, an inductance can be minimized between the decoupling capacitor **103** and the semiconductor integrated circuit chip body **101**. If the decoupling capacitor **103** is disposed on the bottom or the like of the semiconductor integrated circuit chip body **101**, spatial limitations occur when it is mounted on a package substrate. This is because a plurality of input/output terminals (not shown) are disposed normally at the bottom of the semiconductor integrated circuit chip body **101**. Thus, the size of the decoupling capacitor might be limited. As in the current embodiment, the direct disposition of the decoupling capacitor **103** at the side face does not cause such limitation.

FIGS. **2A** through **2C** are views for explaining a semiconductor integrated circuit chip according to another exemplary embodiment of the present invention. FIG. **2A** is a cross-sectional view, and FIGS. **2B** and **2C** are perspective views illustrating the disposition of a decoupling capacitor at a semiconductor integrated circuit chip body in detail.

The current embodiment of FIG. **2A** is similar to the previous embodiment of FIGS. **1A** to **1C** in that a semiconductor integrated circuit chip **200** according to the current embodiment includes a semiconductor integrated circuit chip body **201**, first and second electrode pads **202a** and **202b**, and a decoupling capacitor **203** disposed at a side face of the semiconductor integrated circuit chip body **201**. The difference there is that the first and second electrode pads **202a** and **202b** are not disposed at a side face of the semiconductor integrated circuit chip body **201**, and thus the decoupling capacitor **203** has a clip-like structure, not a hexahedron structure. This will now be described in more detail with reference to FIGS. **2B** and **2C**. The first and second electrode pads **202a** and **202b** are disposed on both top and bottom faces of the semiconductor integrated circuit chip body **201**. The decoupling capacitor **203** includes two protrusions respectively protruding from an upper portion and a lower portion thereof. As a result, the decoupling capacitor **203** may be attached to the semiconductor integrated circuit chip body **201** as a clip-like shape. The decoupling capacitor **203** can be more firmly attached to the semiconductor integrated circuit chip body **201** because of its clip shape.

Although not shown, first and second external electrodes may be formed on the outside of the decoupling capacitor **203** to contact the first and second electrode pads **202a** and **202b**, respectively. The first and second external electrodes are electrically connected to first and second internal electrodes **201a** and **201b**, respectively.

A structure of the decoupling capacitor **203** will now be described in more detail with reference to FIGS. **2B** and **2C**. As shown in FIGS. **2B** and **2C**, a stack direction of the first and second internal electrodes **201a** and **201b**, i.e., a direction in which a plurality of dielectric layers are stacked, corresponds to a direction in which the first and second electrode pads **202a** and **202b** are disposed. When viewed from the top of the semiconductor integrated circuit chip body **201**, first internal electrodes **201a** in a left region, specifically, in the left half of the decoupling capacitor **203** have lead structures extending from their upper portions, respectively. First internal electrodes **201a** in the right half of the decoupling capacitor **203** have lead structures extending from their lower portions, respectively.

In this case, the respective lead structures of the first internal electrodes **201a** extending from their upper portions are electrically connected to the first electrode pad **202a** on a top face of the semiconductor integrated circuit chip body **201**. The respective lead structures of the first internal electrodes **201a** extending from their lower portions are electrically connected to a first electrode pad (not shown) on a bottom face of the semiconductor integrated circuit chip body **201**. Likewise, respective lead structures of the second internal electrodes **201b** extending from their upper portions are electrically connected to the second electrode pad **202b** on the top face of the semiconductor integrated circuit chip body **201**. Respective lead structures of the second internal electrodes **201b** extending from their lower portions are electrically connected to a second electrode pad **202b** on the bottom face of the semiconductor integrated circuit chip body **201**.

That is, the second electrode pad **202b** on the bottom face of the semiconductor integrated circuit chip body **201** faces the first electrode pad **202a** on the top face of the semicon-

7

ductor integrated circuit chip body **201**. Likewise, the first electrode pad **202a** on the bottom face of the semiconductor integrated circuit chip body **201** faces the second electrode pad **202b** on the top face of the semiconductor integrated circuit chip body **201**. When viewed from the top of the semiconductor integrated circuit chip body **201**, the first and second electrode pads **202a** and **202b** overlap each other.

FIGS. **3A** and **3B** are views for explaining a semiconductor integrated circuit chip according to still another exemplary embodiment of the present invention. FIG. **3A** is a cross-sectional view, and FIG. **3B** is a perspective view illustrating the disposition of a decoupling capacitor at a semiconductor integrated circuit chip body in detail.

The current embodiment of FIGS. **3A** and **3B** is similar to the previously embodiments of FIGS. **1A** and **2A** in that a semiconductor integrated circuit chip **300** according to the current embodiment includes a semiconductor integrated circuit chip body **301**, first and second electrode pads **302a** and **302b**, and a decoupling capacitor **303** disposed at a side face of the semiconductor integrated circuit chip body **301**. The difference there is that the decoupling capacitor **303** includes one protrusion protruding from an upper portion. The protrusion covers a portion of a top face of the semiconductor integrated circuit chip body **301**. Also, the first and second electrode pads **302a** and **302b** are disposed only on the top face of the semiconductor integrated circuit chip body **301**. The first and second electrode pads **302a** and **302b** on the top face of the semiconductor integrated circuit chip body **301** are spaced apart from each other along a direction facing the decoupling capacitor **303**.

The decoupling capacitor **303** is attached to the semiconductor integrated circuit chip body **301** having the above structure. As shown in FIG. **3B**, in the decoupling capacitor **303**, a lead structure extending from the second internal electrode **301b** is longer than a lead structure extending from the first internal electrode **301a** in a direction of the semiconductor integrated device chip body **301**. That is, the lead structure extending from the second internal electrode **301b** covers a top portion of the first electrode pad **302a**. As in the previous embodiments, first and second external electrodes may be disposed on outer portions of the decoupling capacitor **303** contacting the first and second electrode pads **302a** and **302b**. The description of the previous embodiments may be applied to the current embodiment of FIGS. **3A** and **3B**, except for the structural difference described above.

Exemplary embodiments of another aspect of the present invention will now be described with reference to FIGS. **4** through **7**. FIG. **4** is a cross-sectional view of a semiconductor integrated circuit chip package according to an exemplary embodiment of the present invention. FIG. **5** is an alternative version of the semiconductor integrated circuit chip package of FIG. **4**.

As shown in FIG. **4**, a semiconductor integrated circuit chip package **400** according to an exemplary embodiment of the present invention includes the same semiconductor integrated circuit chip as that of the embodiment of FIG. **1A**. That is, the semiconductor integrated circuit chip mounted on a package substrate **405** includes a semiconductor integrated circuit chip body **401**, first and second electrode pads **402a** and **402b** disposed at a side face of the semiconductor integrated circuit chip body **401**, and a decoupling capacitor **403** electrically connected to the first and second electrode pads **402a** and **402b**. As shown in FIG. **4**, interconnections such as a power plane PWR Plane, a ground plane GND plane and a conductive via are located on and inside the package substrate **405** in order to supply power to the semiconductor integrated circuit chip body **401**. The power plane and the ground plane

8

of the package substrate **405** may be electrically connected to the semiconductor integrated circuit chip through a via and a bump **404**. As in the current embodiment, the decoupling capacitor **403** is disposed at a side face of the semiconductor integrated circuit chip body **401**, so that a current path between the two can be significantly shortened, and an inductance can be lowered as compared to when the decoupling capacitor **403** is disposed at, e.g., a package substrate **405** or a mother board (not shown).

According to embodiments, a plurality of semiconductor integrated circuit chips may be provided and stacked, electrically connected together by the bump **404** or the like. As shown in FIG. **5**, three semiconductor integrated circuit chip bodies **501** are stacked on the semiconductor integrated circuit chip package **500** and share a decoupling capacitor **503** located at their side faces. That is, the decoupling capacitor **503** may serve as a common decoupling capacitor of the semiconductor integrated circuit chip bodies **501**.

As in the previous embodiments, the decoupling capacitor **503** is electrically connected to first and second electrode pads **502a** and **502b**. For this electrical connection, six external electrodes (not shown) are located on one face of the decoupling capacitor **503** facing the semiconductor integrated circuit chip body **501**. According to the current embodiment, the stack of the semiconductor integrated circuit chips secure high performance and lower the inductance by sharing the one decoupling capacitor **503** located on their side faces. According to the current embodiment, the three semiconductor integrated circuit chip bodies **501** share the one decoupling capacitor **503**. However, the present invention is not limited thereto, and the semiconductor integrated circuit chip bodies **501** may make one-to-one connections with decoupling capacitors.

FIG. **6** is a cross-sectional view of a semiconductor integrated circuit chip package according to another exemplary embodiment of the present invention. FIG. **7** is an alternative version of the semiconductor integrated circuit chip package of FIG. **6**.

Referring to FIG. **6**, a semiconductor integrated circuit chip package **600** according to the current embodiment includes three semiconductor integrated circuit chip bodies **601** mounted on the package substrate **405**, as in the embodiment of FIG. **5**. The embodiments of FIGS. **5** and **6** are different in a structure of electrode pads **602a** and **602b** of a semiconductor integrated circuit chip body **601** and a structure of a decoupling capacitor **603**. The first and second electrode pads **602a** and **602b** are located on a top or bottom surface of the semiconductor integrated circuit chip body **601**, not a side face thereof. The decoupling capacitor **603** includes four protrusions extending from its one side face. As shown in FIG. **6**, the decoupling capacitor **603** having the four protrusions has a comb-like shape when viewed from the side. Thus, the decoupling capacitor **603** can be easily placed by inserting the protrusion in each space between the semiconductor integrated circuit chip bodies **601**. A first or second external electrode is formed at each protrusion of the decoupling capacitor **603** to be properly connected with the first or second electrode pad **602a** or **602b**.

Referring to FIG. **7**, a semiconductor integrated circuit chip package **600'** which is an alternative version of a structure of FIG. **6** further includes a second decoupling capacitor **604** disposed at an opposing side of the decoupling capacitor **603** (hereinafter, also referred to as a first decoupling capacitor). The second decoupling capacitor **604** is structurally similar to the first decoupling capacitor **603**, except that it has only two protrusions forming a clip-like structure. The clip-like structure facilitates the disposition of the second decou-

pling capacitor **604**. As indicated above, a desired number of decoupling capacitors **603** and **604** may be disposed at the side of a stack of the plurality of semiconductor integrated circuit chip bodies **601**. The decoupling capacitors **603** and **604** may have a comb or clip shape so that they can be easily placed at the stack.

An external electrode terminal may be further provided on a bottom face of the decoupling capacitor **603**, that is, on a face of the decoupling capacitor **603** contacting the package substrate **405** so as to provide power to the semiconductor integrated circuit chip bodies **601** through the decoupling capacitor **603**.

According to the present invention, a semiconductor integrated circuit chip can be achieved, which can maintain an impedance of a power distribution network below a target impedance in a wide frequency range, particularly, at a high frequency by minimizing an inductance between a decoupling capacitor and a semiconductor integrated circuit chip.

While the present invention has been shown and described in connection with the exemplary embodiments, it will be apparent to those skilled in the art that modifications and variations can be made without departing from the spirit and scope of the invention as defined by the appended claims.

What is claimed is:

1. A semiconductor integrated circuit chip comprising:
  - a semiconductor integrated circuit chip body;
  - an input/output terminal disposed on the outside of the semiconductor integrated circuit chip body; and
  - a decoupling capacitor disposed at a side face of the semiconductor integrated circuit chip body and electrically connected to the input/output terminal,
 wherein the decoupling capacitor comprises a capacitor body including a stack of a plurality of dielectric layers, and first and second internal electrodes, the first and second internal electrodes having opposite polarities and alternating with each other, one of the plurality of dielectric layers being between each alternate set of the first and second internal electrodes, and having at least one protrusion extending from one side face of the dielectric layers and the first and second internal electrodes, a side face of the dielectric layers and the first and second internal electrodes facing the side face of the chip body are provided such that a top face or a bottom face of the protrusion covers a portion of the chip body, and external electrodes are disposed on the top face or the bottom face of the protrusion toward the chip body.
2. The semiconductor integrated circuit chip of claim 1, wherein the input/output terminal is placed at the side face of the semiconductor integrated circuit chip body at which the decoupling capacitor is disposed.
3. The semiconductor integrated circuit chip of claim 1, wherein the input/output terminal is disposed on at least one of top and bottom faces of the semiconductor integrated circuit chip body.
4. The semiconductor integrated circuit chip of claim 1, wherein the decoupling capacitor comprises:
  - a capacitor body including therein a stack of a plurality of dielectric layers;
  - first and second internal electrodes having opposite polarity and alternated with each other, with the dielectric layer between each alternate set of the first and second internal electrodes; and
  - first and second external electrodes disposed on the outside of the capacitor body and respectively connected to the first and second internal electrodes.
5. The semiconductor integrated circuit chip of claim 4, wherein the first and second external electrodes are disposed

in one direction on a side face of the capacitor body facing the semiconductor integrated circuit chip body, and are spaced apart from each other.

6. The semiconductor integrated circuit chip of claim 4, wherein the input/output terminal comprises first and second electrode pads electrically connected to the first and second external electrodes, respectively.

7. The semiconductor integrated circuit chip of claim 6, wherein the first and second electrode pads are disposed on both top and bottom faces of the semiconductor integrated circuit chip body.

8. The semiconductor integrated circuit chip of claim 7, wherein the first and second electrode pads on the same face are spaced apart from each other in a direction perpendicular to a direction from the semiconductor integrated circuit chip body toward the decoupling capacitor.

9. The semiconductor integrated circuit chip of claim 8, wherein the second electrode pad on the bottom face of the semiconductor integrated circuit chip body faces the first electrode pad on the top face of the semiconductor integrated circuit chip body.

10. The semiconductor integrated circuit chip of claim 8, wherein the plurality of dielectric layers are stacked in the same direction as a direction in which the first and second electrode pads are disposed.

11. The semiconductor integrated circuit chip of claim 5, wherein the first and second electrode pads are disposed on a top or bottom face of the semiconductor integrated circuit chip body.

12. The semiconductor integrated circuit chip of claim 11, wherein the first and second electrode pads are spaced apart from each other in a direction from the semiconductor integrated circuit chip body toward the decoupling capacitor.

13. A multilayer chip capacitor comprising:
 

- a capacitor body having a shape defined by top and bottom faces facing each other and side faces therebetween, and including therein a stack of a plurality of dielectric layers;
- first and second internal electrodes having opposite polarity and alternating with each other, with the dielectric layer between each alternate set of the first and second internal electrodes; and

first and second external electrodes disposed on the outside of the capacitor body and electrically connected to the first and second internal electrodes, respectively, wherein the capacitor body includes at least one protrusion extending from one side face of the dielectric layers and the first and second internal electrodes, a side face of the dielectric layers and the first and second internal electrodes facing the side face of the chip body are provided such that a top face or a bottom face of the protrusion covers a portion of the chip body, and the first and second external electrodes are disposed on the top face or the bottom face of the protrusion toward the chip body.

14. The multilayer chip capacitor of claim 13, wherein the capacitor body includes one protrusion extending from the top face and the side face of the dielectric layers and the first and second internal electrodes, and the first and second external electrodes are disposed on a face facing a lower portion of the capacitor body among faces forming the protrusion.

15. The multilayer chip capacitor of claim 14, wherein the first and second external electrodes are spaced apart from each other in a direction from the protrusion toward the capacitor body.

## 11

16. The multilayer chip capacitor of claim 14, wherein the plurality of dielectric layers are stacked in a direction perpendicular to a direction in which the first and second external electrodes are disposed.

17. The multilayer chip capacitor of claim 13, wherein the capacitor body includes a first protrusion extending from the top face and the side face of the dielectric layers and the first and second internal electrodes, and a second protrusion extending from the bottom face and the side face of the dielectric layers and the first and second internal electrodes, and

the first and second external electrodes are disposed on a face facing a lower portion of the capacitor body among faces forming the first protrusion and on a face facing an upper portion of the capacitor body among faces forming the second protrusion.

18. The multilayer chip capacitor of claim 17, wherein the first and second external electrodes at the first protrusion are spaced from each other in a direction perpendicular to a direction from the first protrusion toward the capacitor body, and

the first and second external electrodes at the second protrusion are spaced apart from each other in a direction perpendicular to a direction from the second protrusion toward the capacitor body.

19. The multilayer chip capacitor of claim 18, wherein the second external electrode at the second protrusion faces the first external electrode at the first protrusion.

20. The multilayer chip capacitor of claim 18, wherein the plurality of dielectric layers are stacked in a direction in which the first and second external electrodes are disposed.

21. The multilayer chip capacitor of claim 13, wherein the capacitor body includes a plurality of protrusions extended from the dielectric layers and the first and second internal electrodes and disposed spaced apart from each other in one direction.

22. A semiconductor integrated circuit chip package comprising:

a package substrate; and

a semiconductor integrated circuit chip mounted on the package substrate and including a semiconductor integrated circuit chip body, an input/output terminal disposed on the outside of the semiconductor integrated circuit chip body, and a decoupling capacitor disposed at a side face of the semiconductor integrated circuit chip body and electrically connected to the input/output terminal,

## 12

wherein the decoupling capacitor comprises a capacitor body including a stack of a plurality of dielectric layers, and first and second internal electrodes, the first and second internal electrodes having opposite polarities and alternating with each other, one of the plurality of dielectric layer being between each alternate set of the first and second internal electrodes, and

having at least one protrusion extending from one side face of the dielectric layers and the first and second internal electrodes, a side face of the dielectric layers and the first and second internal electrodes facing the side face of the chip body are provided such that a top face or a bottom face of the protrusion covers a portion of the chip body, and external electrodes are disposed on the top face or the bottom face of the protrusion toward the chip body.

23. The semiconductor integrated circuit chip package of claim 22, wherein the semiconductor integrated circuit chip comprises a plurality of semiconductor integrated circuit chips stacked on top of each other on the package substrate.

24. The semiconductor integrated circuit chip package of claim 23, wherein the decoupling capacitor is a common decoupling capacitor electrically connected to at least two semiconductor integrated circuit chips of the plurality of semiconductor integrated circuit chips.

25. The semiconductor integrated circuit chip package of claim 23, wherein the decoupling capacitor includes:

at least one protrusion extending from a side face of the decoupling capacitor facing the semiconductor integrated circuit chip body; and

first and second external electrodes disposed at a face forming the protrusion and electrically connected to the input/output terminal.

26. The semiconductor integrated circuit chip package of claim 25, wherein the protrusion is placed in a space between an adjacent set of the semiconductor integrated circuit chips.

27. The semiconductor integrated circuit chip package of claim 22, further comprising an external electrode provided on one side of the decoupling capacitor and contacting a top face of the package substrate to be electrically connected with the package substrate,

wherein the semiconductor integrated circuit chip body is electrically connected with the package substrate through the decoupling capacitor.

\* \* \* \* \*